

MBN1200H45E2-H

Preliminary Specification

Silicon N-channel IGBT 4500V E2 version

FEATURES

- * Low switching loss IGBT module.
- * Low noise due to ultra soft fast recovery diode.
- * High reliability, high durability module.
- * High thermal fatigue durability.
($\Delta T_c=70^\circ\text{C}$, $N>30,000$ cycles)
- * Isolated heat sink (terminal to base).

ABSOLUTE MAXIMUM RATINGS ($T_c=25^\circ\text{C}$)

Item	Symbol	Unit	MBN1200H45E2-H
Collector Emitter Voltage	V_{CES}	V	4,500
Gate Emitter Voltage	V_{GES}	V	± 20
Collector Current	DC	I_C	1,200 ($T_c=80^\circ\text{C}$)
	1ms	I_{Cp}	2,400
Forward Current	DC	I_F	1,200
	1ms	I_{FM}	2,400
Junction Temperature	T_j	$^\circ\text{C}$	-40 ~ +125
Storage Temperature	T_{stg}	$^\circ\text{C}$	-50 ~ +125
Isolation Voltage	V_{ISO}	V_{RMS}	8,400 (AC 1 minute)
Screw Torque	Terminals (M4/M8)	-	2/10 (1)
	Mounting (M6)	-	6 (2)

Notes: (1) Recommended Value $1.8\pm 0.2/9\pm 1\text{N}\cdot\text{m}$ (2) Recommended Value $5.5\pm 0.5\text{N}\cdot\text{m}$ **ELECTRICAL CHARACTERISTICS**

Item	Symbol	Unit	Min.	Typ.	Max.	Test Conditions	
Collector Emitter Cut-Off Current	I_{CES}	mA	-	-	25	$V_{CE}=4,500\text{V}$, $V_{GE}=0\text{V}$, $T_j=25^\circ\text{C}$	
			-	25	100	$V_{CE}=4,500\text{V}$, $V_{GE}=0\text{V}$, $T_j=125^\circ\text{C}$	
Gate Emitter Leakage Current	I_{GES}	nA	-500	-	+500	$V_{GE}=\pm 20\text{V}$, $V_{CE}=0\text{V}$, $T_j=25^\circ\text{C}$	
Collector Emitter Saturation Voltage	$V_{CE(sat)}$	V	TBD	4.2	4.7	$I_C=1200\text{A}$, $V_{GE}=15\text{V}$, $T_j=125^\circ\text{C}$	
Gate Emitter Threshold Voltage	$V_{GE(TO)}$	V	5.4	6.4	7.4	$V_{CE}=10\text{V}$, $I_C=1200\text{mA}$, $T_j=25^\circ\text{C}$	
Input Capacitance	C_{ies}	nF	-	165	-	$V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{kHz}$, $T_j=25^\circ\text{C}$	
Internal Gate Resistance	R_{ge}	Ω	-	0.8	-	$V_{CE}=10\text{V}$, $V_{GE}=0\text{V}$, $f=100\text{kHz}$, $T_j=25^\circ\text{C}$	
Switching Times	Rise Time	t_r	-	2.1	4.2	$V_{CC}=2,600\text{V}$, $I_C=1200\text{A}$	
	Turn On Time	t_{on}	-	2.7	5.4	$L_s=150\text{nH}$	
	Fall Time	t_f	-	2.4	3.6	$R_G=3.3\Omega$ (3)	
	Turn Off Time	t_{off}	-	4.8	7.2	$V_{GE}=\pm 15\text{V}$, $T_j=125^\circ\text{C}$	
Peak Forward Voltage Drop	V_{FM}	V	TBD	3.7	4.2	$I_F=1200\text{A}$, $V_{GE}=0\text{V}$, $T_j=125^\circ\text{C}$	
Reverse Recovery Time	t_{rr}	μs	-	0.7	1.4	$V_{CC}=2600\text{V}$, $I_F=1200\text{A}$, $L_s=150\text{nH}$, $T_j=125^\circ\text{C}$	
Turn On Loss	$E_{on(10\%)}$	J/p	-	3.2	4.8	$V_{CC}=2600\text{V}$, $I_C=I_F=1200\text{A}$, $L_s=150\text{nH}$, $R_G=3.3\Omega$ (3), $V_{GE}=\pm 15\text{V}$, $T_j=125^\circ\text{C}$	
	$E_{on(full)}$	J/p	-	3.8	-		
Turn Off Loss	$E_{off(10\%)}$	J/p	-	3.2	4.8		
	$E_{off(full)}$	J/p	-	3.8	-		
Reverse Recovery Loss	$E_{rr(10\%)}$	J/p	-	2.5	3.7		
	$E_{rr(full)}$	J/p	-	2.8	-		
Thermal Impedance	IGBT	$R_{th(j-c)}$	K/W	-	-	0.0085	Junction to case
	FWD	$R_{th(j-c)}$	K/W	-	-	0.017	
Contact Thermal Impedance		$R_{th(c-f)}$	K/W	-	0.005	-	Case to fin ($\lambda_{grease}=1\text{W}/(\text{m}\cdot\text{K})$, Heat-sink flatness $\leq 50\mu\text{m}$)

Notes:(3) R_G value is the test condition's value for evaluation of the switching times, not recommended value.Please, determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted.

* Please contact our representatives at order.

* For improvement, specifications are subject to change without notice.

* For actual application, please confirm this spec sheet is the newest revision.

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DEFINITION OF TEST CIRCUIT

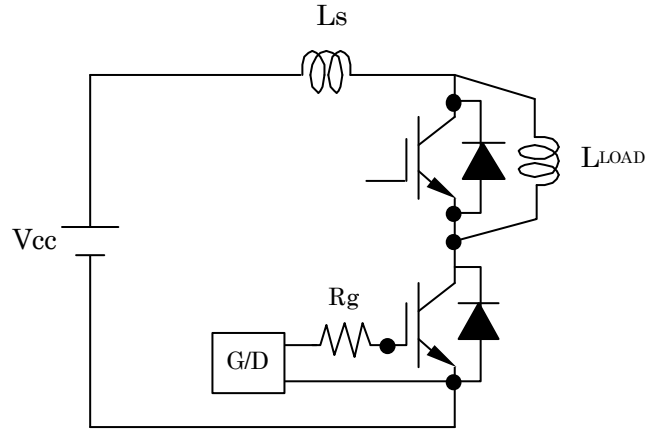


Fig.1 Switching test circuit

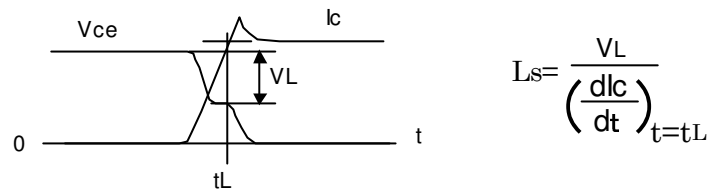


Fig.2 Definition of Ls

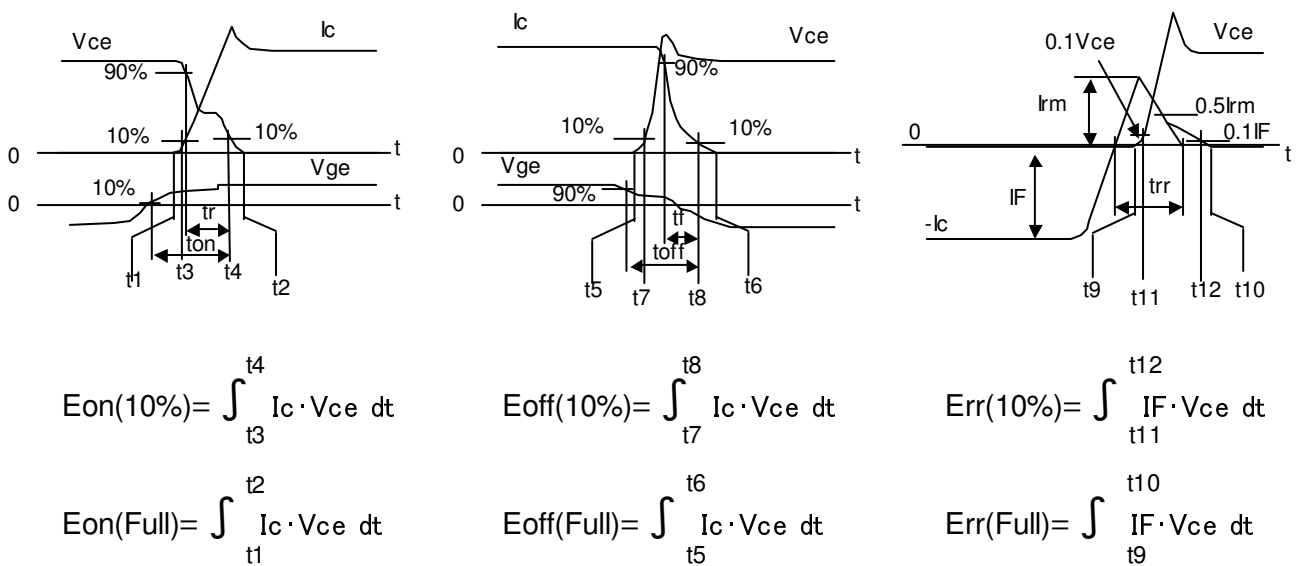
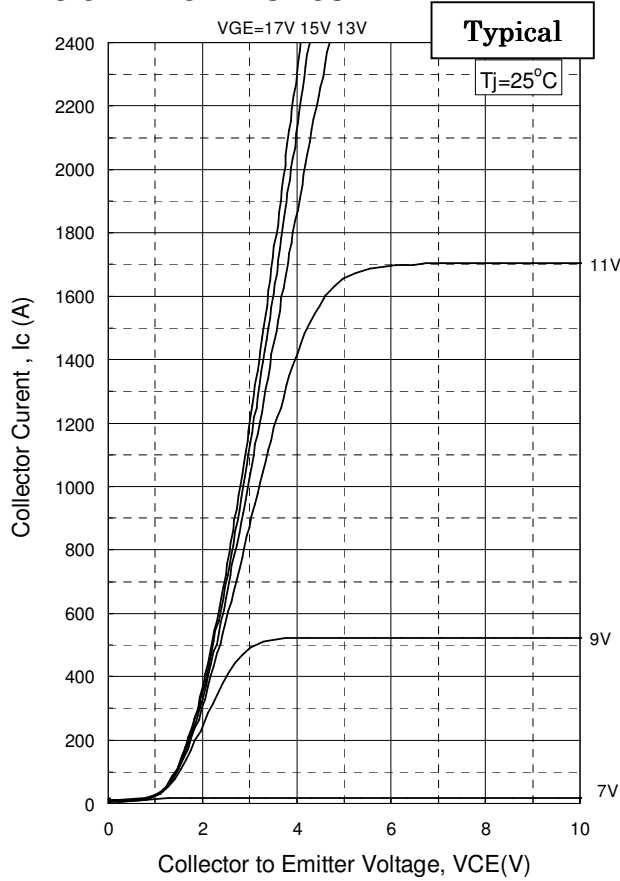


Fig.3 Definition of switching loss

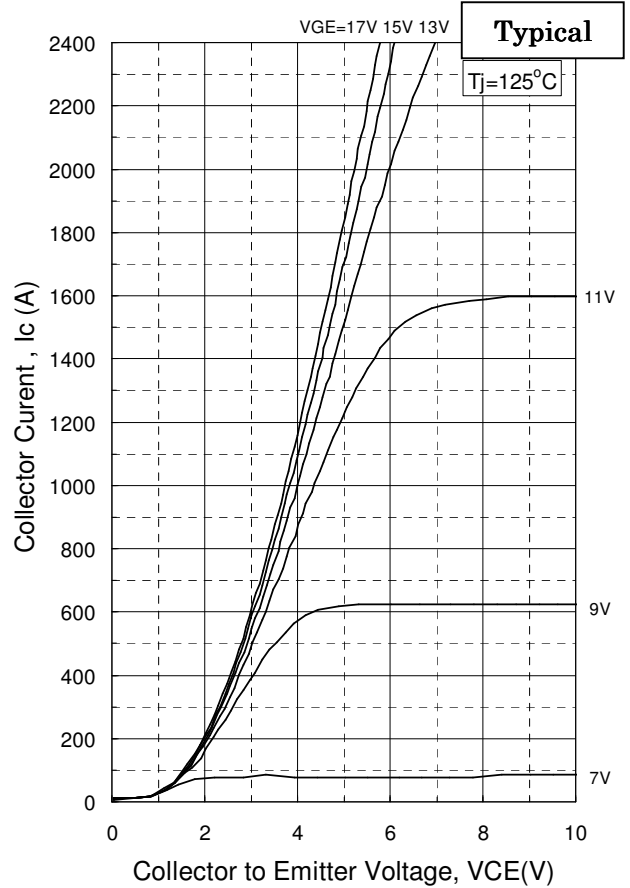
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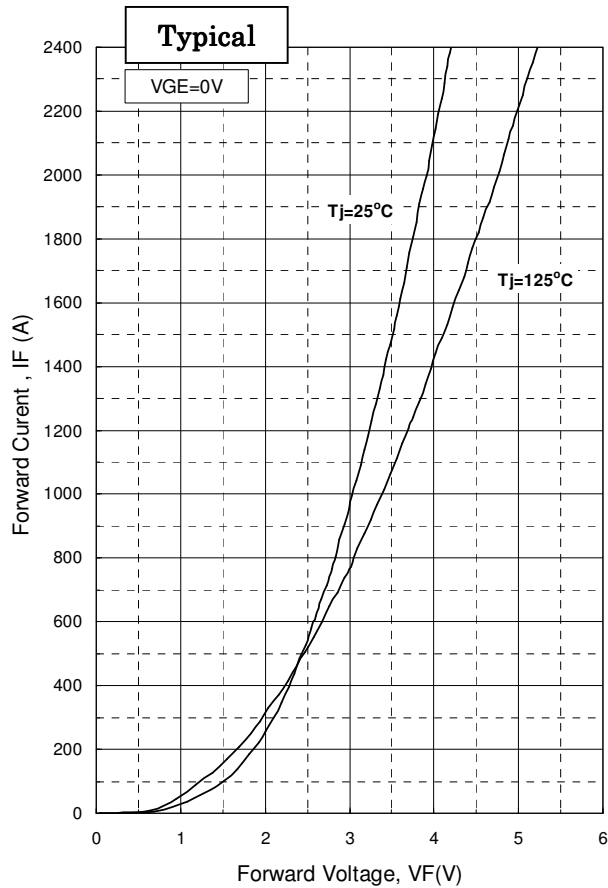
STATIC CHARACTERISTICS



I_c vs. V_{CE}(T_j=25°C)



I_c vs. V_{CE}(T_j=125°C)

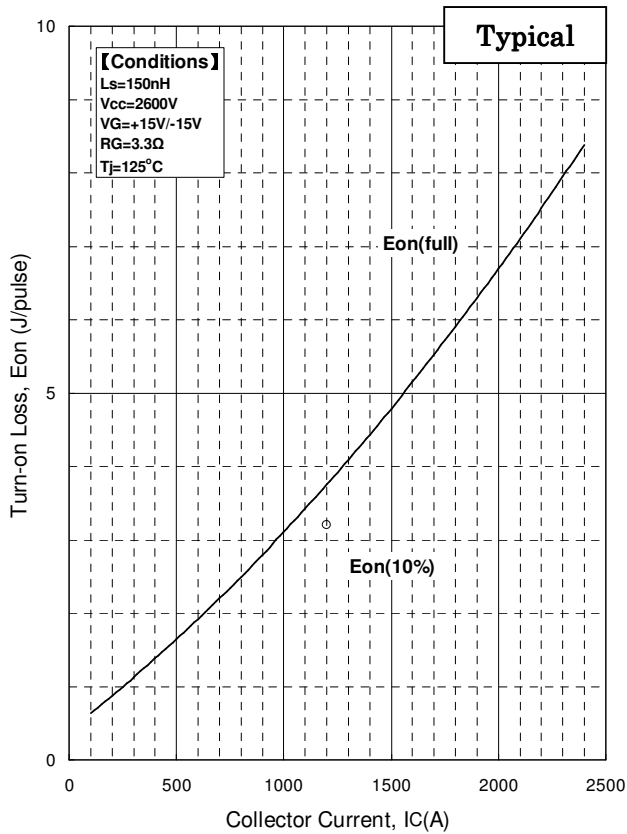


I_F vs. V_F

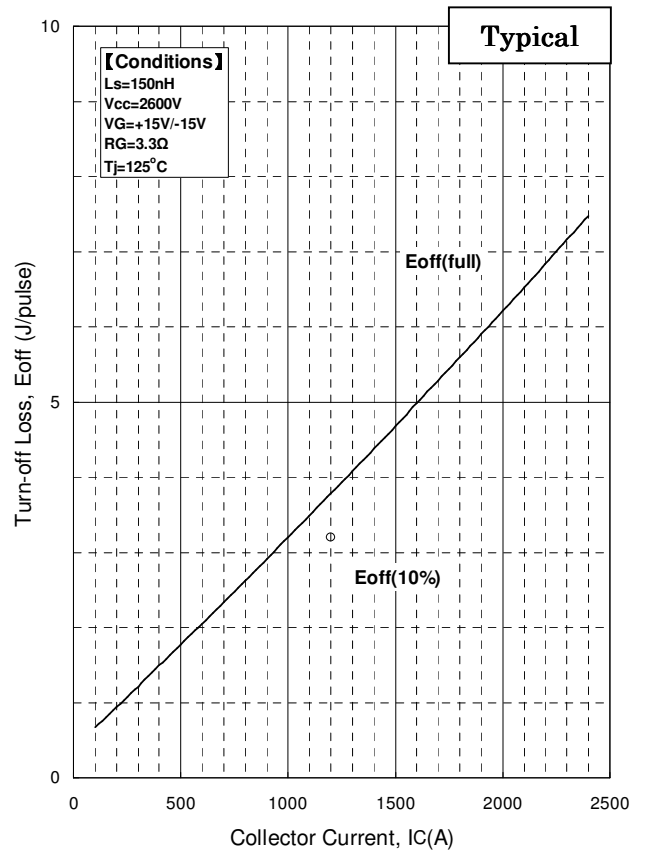
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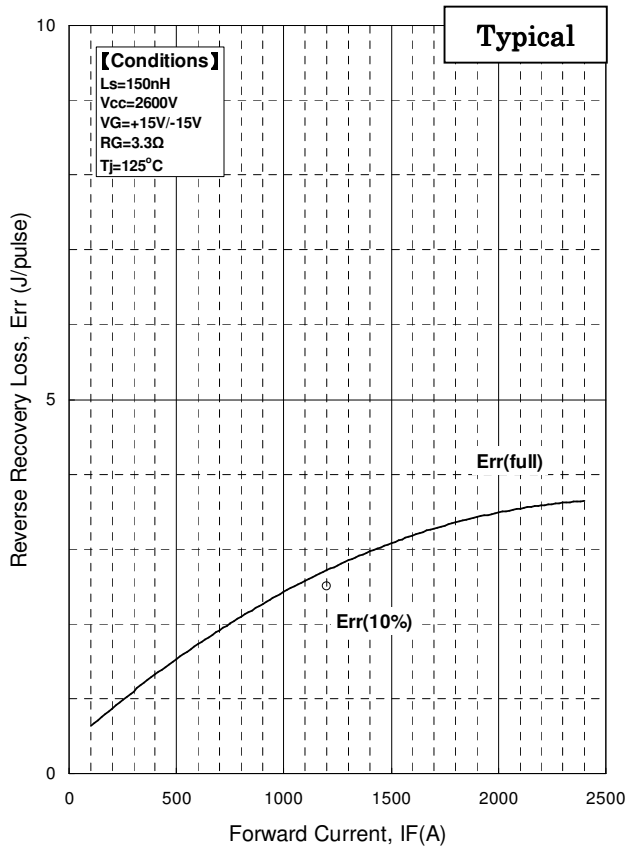
DYNAMIC CHARACTERISTICS



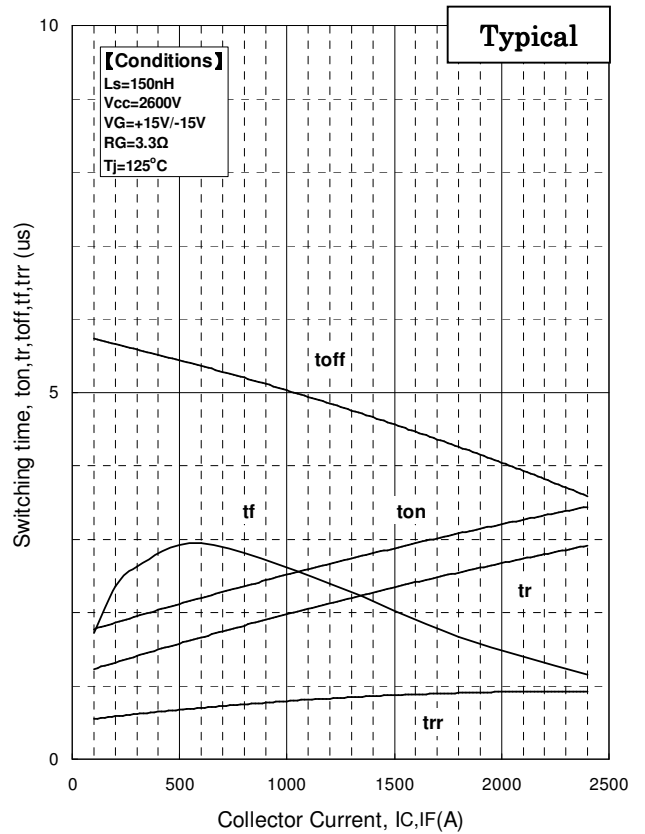
Turn-on loss vs. Collector current



Turn-off loss vs. Collector current



Recovery loss vs. Forward current

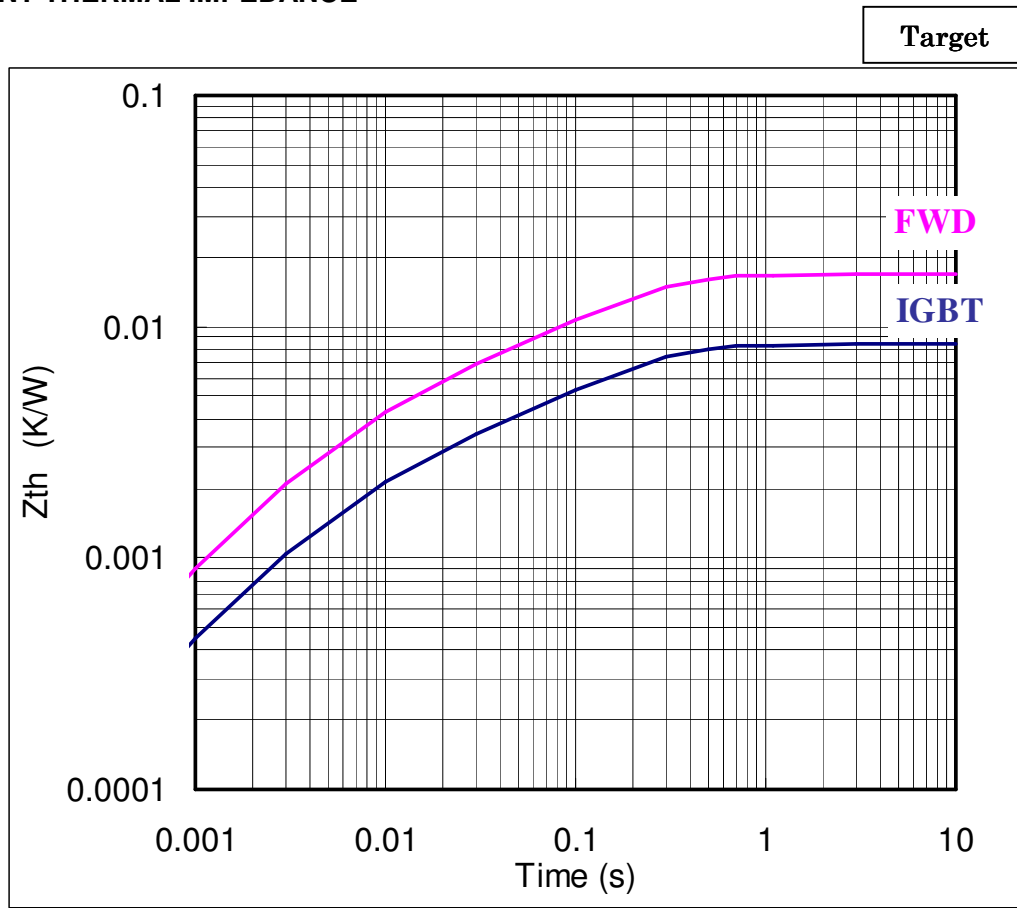


Switching time vs. Collector current

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TRANSIENT THERMAL IMPEDANCE



Transient Thermal Impedance Curve (Maximum Value)

- **Negative environmental impact material**

Please note that following materials are contained in the product
 In order to keep characteristics and reliability level.

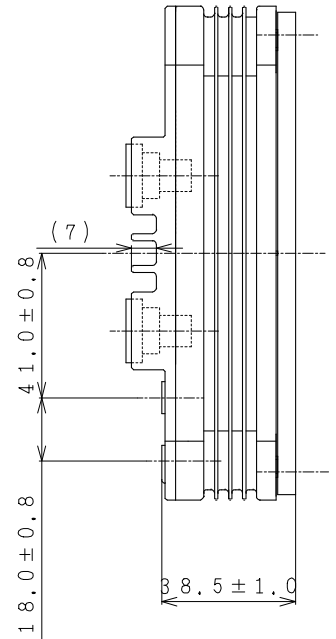
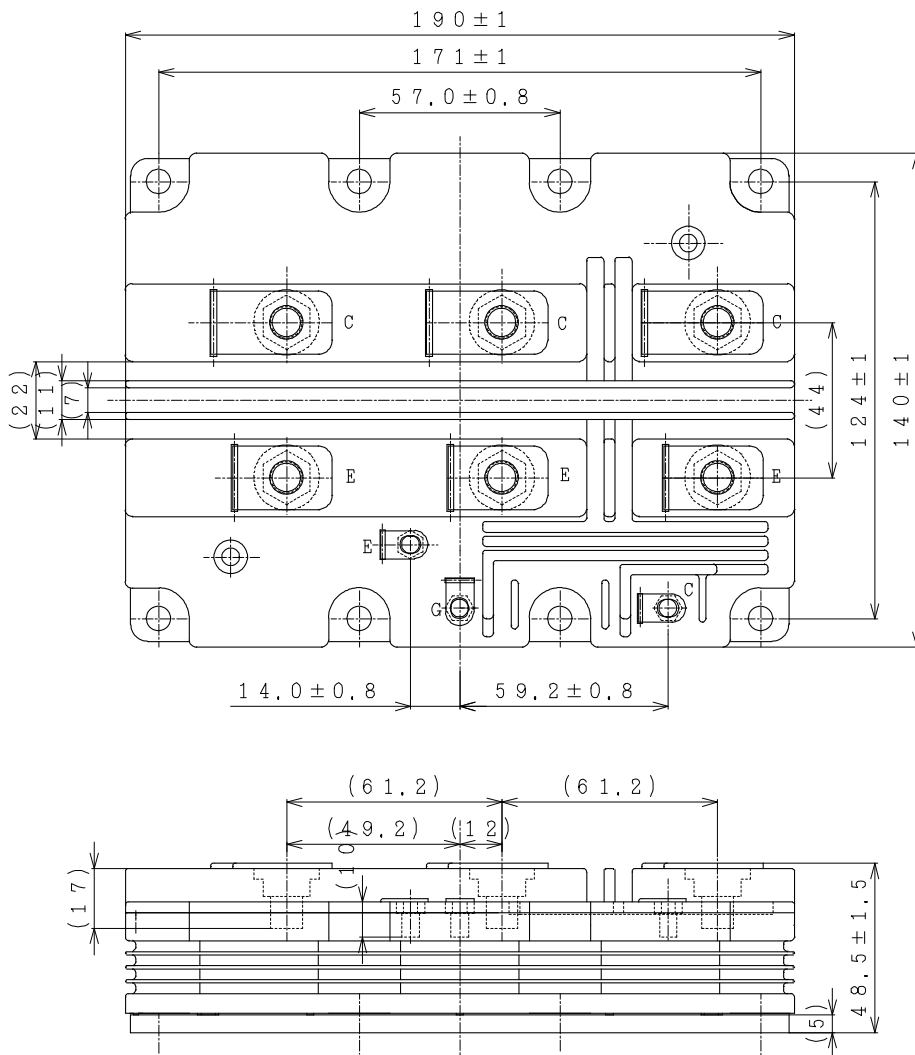
Material	Contained part
Lead (Pb) and its compounds	Solder
Arsenic and its compounds	Si chip

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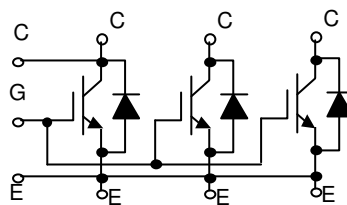
Module Outline Drawing

Unit: mm



Weight: 1550(g)

CIRCUIT DIAGRAM



TERMINALS

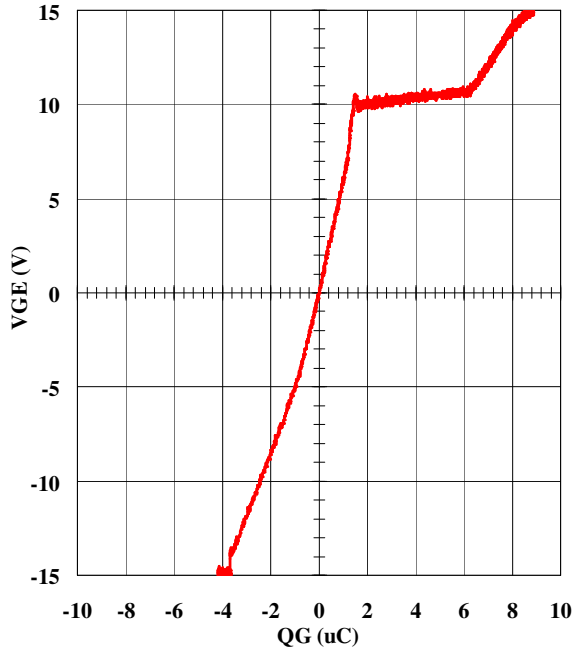
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QG-VGE Curve

TYPICAL

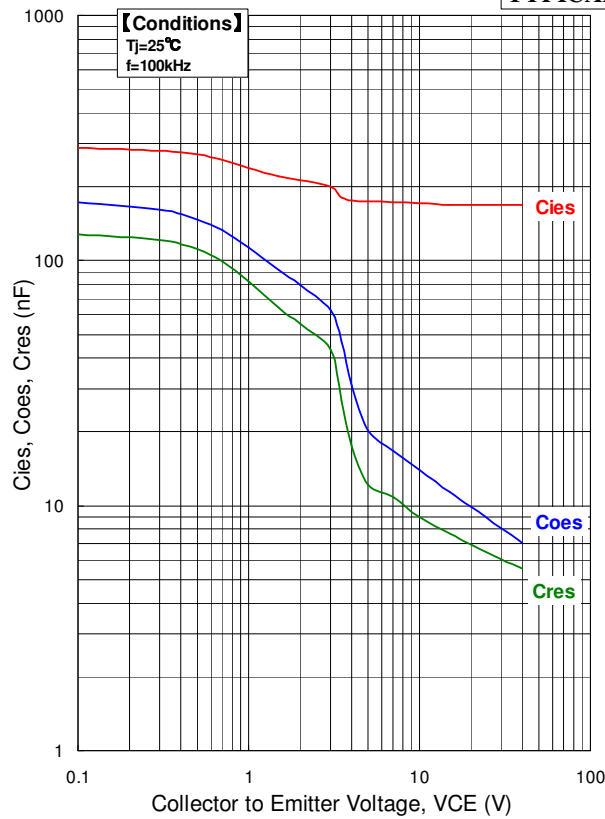
Conditions: $L_s=150\text{nH}$, $V_{CC}=2600\text{V}$, $V_{GE}=\pm 15\text{V}$,
 $R_{G(\text{on/off})}=27\Omega/27\Omega$, $T_j=25^\circ\text{C}$,



QG-VGE curve

Cies, Coes, Cres Curve

TYPICAL



Capacitance vs. Collector to Emitter Voltage

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HITACHI POWER SEMICONDUCTORS

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